

**Notice of References Cited**

Application/Control No.

09/670,917

Applicant(s)/Patent Under

Reexamination

MIZUNO ET AL.

Examiner

Maria Guerrero

Art Unit

2822

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	B	US-4,720,395	01-1988	Foster	427/162
	C	US-6,255,222	07-2001	Xia et al.	438/710
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	N	JP 06080962 A	03-1994	Japan	Mori et al.	252/79.3
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**NON-PATENT DOCUMENTS**

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	U	Mori et al. (JP 06080962 A), Translation
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	W	Ino et al. "Plasma Enhanced In Situ Chamber Cleaning Evaluated by Extracted-Plasma-Parameter Analysis", IEEE, Vol. 9, No. 2, May 1996, pages 230-240.
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.